2011 Beamline Development Proposals National Synchrotron Light Source II

- High-energy x-ray micro-mapping of materials for advanced energy and structural engineering applications beamline (HEX)
 Spokesperson: Mark Croft, Rutgers University
 Source: Superconducting wiggler
- 2. NSLS-II Beamline for Combined High Magnetic Field and High Pressure Materials Studies (HMP) Trevor Tyson, New Jersey Institute of Technology Dipole wiggler
- **3. High-energy macromolecular crystallography (HMX)** Vivian Stojanoff, Brookhaven National Laboratory
- 4. Monochromatic/White Beam X-ray Topography and High Resolution Diffraction Beamline at NSLS-II (HXT) Michael Dudley, Stony Brook University
- 5. Beamline for in situ studies of chemical transformations by scattering measurements with 60-80KeV X-rays (ICT) Jon Hanson, Brookhaven National Laboratory Superconducting wiggler
- 6. Low-energy Anomalous X-ray Diffraction Beamline (LAX) Wayne Hendrickson, Columbia University Canted undulator
- 7. Micron-scale Detector-response Mapping (MDM) for Investigating the Nonuniformity in the X-Ray and Gamma-ray Response of Large-Area/Volume Radiation Detectors (MDM) Ralph James, Brookhaven National Laboratory Three-pole wiggler
- 8. A Superconducting Wiggler Long Beamline at the NSLS-II for Medical Imaging and Radiation Therapy ((MIT)
 F. Avraham Dilmanian, Brookhaven National Laboratory Superconducting wiggler
- **9. REAL time and in-situ studies of Materials in a Radiation Environment (MRE)** Lynne Ecker, Brookhaven National Laboratory

- **10. Soft X-ray Spectromicroscopy Facility for Material Science (SMF)** Konstantine Kaznatcheev, Brookhaven National Laboratory Insertion device
- **11. Scanning Transmission X-ray Microscope (STX)** Juergen Thieme, Brookhaven National Laboratory Bending magnet
- 12. Beamline for studying the electronic properties of nanomaterials and chemical transformations by high-resolution photoemission and near-edge x-ray absorption fine structure (SXS) David Mullins, Oak Ridge National Laboratory Bending magnet
- **13. Combining Operando X-ray Absorption Spectroscopy and Sub-Ångstrom Electron Microscopy (XEM)** Eric Stach
- **14. Versatile Instrument for Spectroscopy (VIS)** Dario Arena Elliptically polarized undulator